

Search Notes

Application/Control No.

10/813,161

Examiner

James D. Stein

Applicant(s)/Patent under
Reexamination

CARR, CHARLES D.

Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner
385	52,88,90 91 and 97	5/22/2006	JDS
216	24	5/22/2006	JDS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
USPGPUB interference search -- see attached EAST search hist		5/22/2006	JDS

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached EAST search history	5/22/2006	JDS
IEEE and INSPEC: optical, alignment, rotate, slide, plate, slab, substrate, bench, etching, tolerance	5/22/2006	JDS
PLUS keyword search	5/22/2006	JDS
USPGPUB interference search -- see attached EAST search history	5/22/2006	JDS